



October 2001
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74ALVC16373

Low Voltage 16-Bit Transparent Latch with 3.6V Tolerant Inputs and Outputs

General Description

The ALVC16373 contains sixteen non-inverting latches with 3-STATE outputs and is intended for bus oriented applications. The device is byte controlled. The flip-flops appear to be transparent to the data when the Latch Enable (LE) is HIGH. When LE is LOW, the data that meets the setup time is latched. Data appears on the bus when the Output Enable (\overline{OE}) is LOW. When \overline{OE} is HIGH, the outputs are in a high impedance state.

The 74ALVC16373 is designed for low voltage (1.1V to 3.6V) V_{CC} applications with I/O compatibility up to 3.6V.

The 74ALVC16373 is fabricated with an advanced CMOS technology to achieve high speed operation while maintaining low CMOS power dissipation.

Features

- 1.1V to 3.6V V_{CC} supply operation
- 3.6V tolerant inputs and outputs
- t_{PD} (I_n to O_n)
 - 3.5 ns max for 3.0V to 3.6V V_{CC}
 - 3.9 ns max for 2.3V to 2.7V V_{CC}
 - 6.8 ns max for 1.65V to 1.95V V_{CC}
- Power-off high impedance inputs and outputs
- Support live insertion and withdrawal (Note 1)
- Uses patented noise/EMI reduction circuitry
- Latchup conforms to JEDEC JED78
- ESD performance:
 - Human body model > 2000V
 - Machine model > 200V
- Also packaged in plastic Fine-Pitch Ball Grid Array (FBGA) (Preliminary)

Note 1: To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pull-up resistor; the minimum value of the resistor is determined by the current-sourcing capability of the driver.

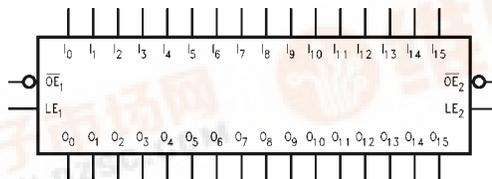
Ordering Code:

Order Number	Package Number	Package Description
74ALVC16373GX (Note 2)	BGA54A (Preliminary)	54-Ball Fine-Pitch Ball Grid Array (FBGA), JEDEC MO-205, 5.5mm Wide [TAPE and REEL]
74ALVC16373MTD (Note 3)	MTD48	48-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide

Note 2: BGA package available in Tape and Reel only.

Note 3: Devices also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.

Logic Symbol

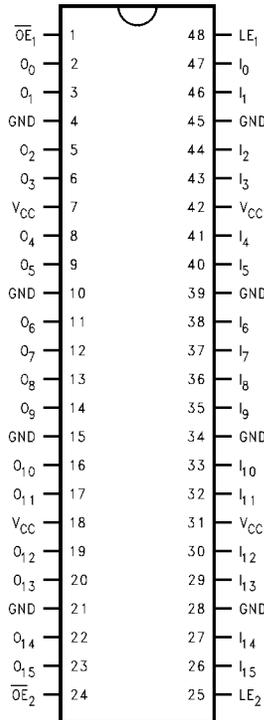


74ALVC16373 Low Voltage 16-Bit Transparent Latch with 3.6V Tolerant Inputs and Outputs

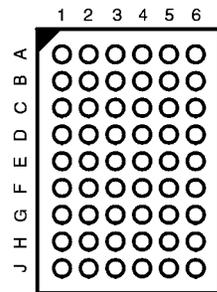


Connection Diagrams

Pin Assignment for TSSOP



Pin Assignment for FBGA



(Top Thru View)

Pin Descriptions

Pin Names	Description
\overline{OE}_n	Output Enable Input (Active LOW)
LE_n	Latch Enable Input
I_0-I_{15}	Inputs
O_0-O_{15}	Outputs
NC	No Connect

FBGA Pin Assignments

	1	2	3	4	5	6
A	O_0	NC	\overline{OE}_1	LE_1	NC	I_0
B	O_2	O_1	NC	NC	I_1	I_2
C	O_4	O_3	V_{CC}	V_{CC}	I_3	I_4
D	O_6	O_5	GND	GND	I_5	I_6
E	O_8	O_7	GND	GND	I_7	I_8
F	O_{10}	O_9	GND	GND	I_9	I_{10}
G	O_{12}	O_{11}	V_{CC}	V_{CC}	I_{11}	I_{12}
H	O_{14}	O_{13}	NC	NC	I_{13}	I_{14}
J	O_{15}	NC	\overline{OE}_2	LE_2	NC	I_{15}

Truth Tables

Inputs			Outputs
LE_1	\overline{OE}_1	I_0-I_7	O_0-O_7
X	H	X	Z
H	L	L	L
H	L	H	H
L	L	X	O_0

Inputs			Outputs
LE_2	\overline{OE}_2	I_8-I_{15}	O_8-O_{15}
X	H	X	Z
H	L	L	L
H	L	H	H
L	L	X	O_0

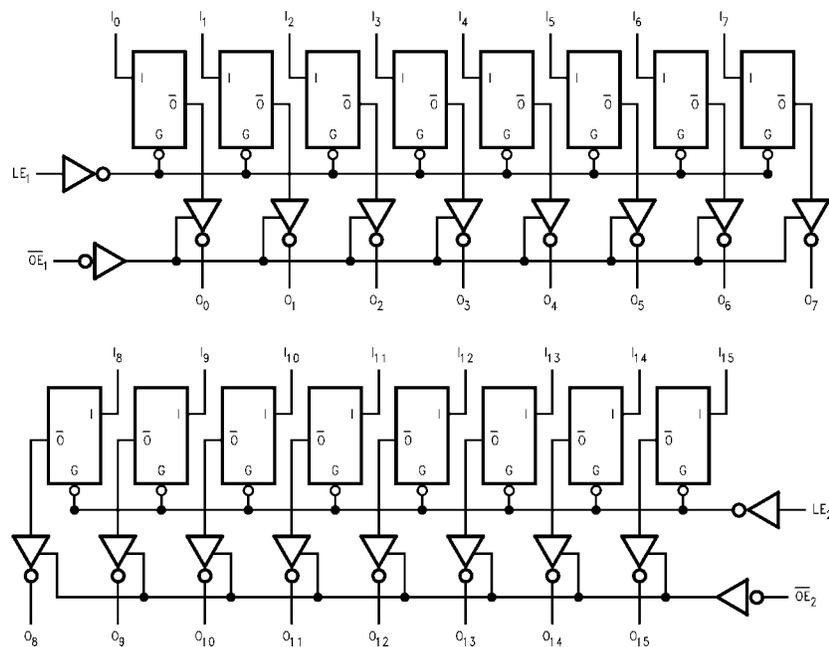
H = HIGH Voltage Level
 L = LOW Voltage Level
 X = Immaterial (HIGH or LOW, inputs may not float)
 Z = High Impedance
 O_0 = Previous O_0 before HIGH-to-LOW of Latch Enable

Functional Description

The 74ALVC16373 contains sixteen edge D-type latches with 3-STATE outputs. The device is byte controlled with each byte functioning identically, but independent of the other. Control pins can be shorted together to obtain full 16-bit operation. The following description applies to each byte. When the Latch Enable (LE_n) input is HIGH, data on the I_n enters the latches. In this condition the latches are transparent, i.e., a latch output will change state each time

its I input changes. When LE_n is LOW, the latches store information that was present on the I inputs a setup time preceding the HIGH-to-LOW transition on LE_n . The 3-STATE outputs are controlled by the Output Enable (\overline{OE}_n) input. When \overline{OE}_n is LOW the standard outputs are in the 2-state mode. When \overline{OE}_n is HIGH, the standard outputs are in the high impedance mode but this does not interfere with entering new data into the latches.

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings (Note 4)

Supply Voltage (V_{CC})	-0.5V to +4.6V
DC Input Voltage (V_I)	-0.5V to 4.6V
Output Voltage (V_O) (Note 5)	-0.5V to $V_{CC} + 0.5V$
DC Input Diode Current (I_{IK})	
$V_I < 0V$	-50 mA
DC Output Diode Current (I_{OK})	
$V_O < 0V$	-50 mA
DC Output Source/Sink Current (I_{OH}/I_{OL})	±50 mA
DC V_{CC} or GND Current per Supply Pin (I_{CC} or GND)	±100 mA
Storage Temperature Range (T_{STG})	-65°C to +150°C

Recommended Operating Conditions (Note 6)

Power Supply	
Operating	1.65V to 3.6V
Input Voltage (V_I)	0V to V_{CC}
Output Voltage (V_O)	0V to V_{CC}
Free Air Operating Temperature (T_A)	-40°C to +85°C
Minimum Input Edge Rate ($\Delta t/\Delta V$)	
$V_{IN} = 0.8V$ to $2.0V$, $V_{CC} = 3.0V$	10 ns/V

Note 4: The Absolute Maximum Ratings are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the Electrical Characteristics tables are not guaranteed at the Absolute Maximum Ratings. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

Note 5: I_O Absolute Maximum Rating must be observed.

Note 6: Floating or unused inputs must be held HIGH or LOW.

DC Electrical Characteristics

Symbol	Parameter	Conditions	V_{CC} (V)	Min	Max	Units
V_{IH}	HIGH Level Input Voltage		1.65 - 1.95 2.3 - 2.7 2.7 - 3.6	0.65 x V_{CC} 1.7 2.0		V
V_{IL}	LOW Level Input Voltage		1.65 - 1.95 2.3 - 2.7 2.7 - 3.6		0.35 x V_{CC} 0.7 0.8	V
V_{OH}	HIGH Level Output Voltage	$I_{OH} = -100 \mu A$ $I_{OH} = -4 mA$ $I_{OH} = -6 mA$ $I_{OH} = -12 mA$ $I_{OH} = -24 mA$	1.65 - 3.6 1.65 2.3 2.3 2.7 3.0 3.0	$V_{CC} - 0.2$ 1.2 2 1.7 2.2 2.4 2		V
V_{OL}	LOW Level Output Voltage	$I_{OL} = 100 \mu A$ $I_{OL} = 4 mA$ $I_{OL} = 6 mA$ $I_{OL} = 12 mA$ $I_{OL} = 24 mA$	1.65 - 3.6 1.65 2.3 2.3 2.7 3		0.2 0.45 0.4 0.7 0.4 0.55	V
I_I	Input Leakage Current	$0 \leq V_I \leq 3.6V$	3.6		±5.0	μA
I_{OZ}	3-STATE Output Leakage	$0 \leq V_O \leq 3.6V$	3.6		±10	μA
I_{CC}	Quiescent Supply Current	$V_I = V_{CC}$ or GND, $I_O = 0$	3.6		40	μA
ΔI_{CC}	Increase in I_{CC} per Input	$V_{IH} = V_{CC} - 0.6V$	3 - 3.6		750	μA

AC Electrical Characteristics										
Symbol	Parameter	$T_A = -40^\circ\text{C to } +85^\circ\text{C}, R_L = 500\Omega$								Units
		$C_L = 50\text{ pF}$				$C_L = 30\text{ pF}$				
		$V_{CC} = 3.3V \pm 0.3V$		$V_{CC} = 2.7V$		$V_{CC} = 2.5V \pm 0.2V$		$V_{CC} = 1.8V \pm 0.15V$		
		Min	Max	Min	Max	Min	Max	Min	Max	
t_{PHL}, t_{PLH}	Propagation Delay Bus to Bus	1.3	3.5	1.5	3.9	1.0	3.4	1.5	6.8	ns
t_{PHL}, t_{PLH}	Propagation Delay LE to Bus	1.3	3.5	1.5	4.4	1.0	3.9	1.5	7.8	ns
t_{PZL}, t_{PZH}	Output Enable Time	1.3	4.0	1.5	5.1	1.0	4.6	1.5	9.2	ns
t_{PLZ}, t_{PHZ}	Output Disable Time	1.3	4.0	1.5	4.3	1.0	3.8	1.5	6.8	ns
Capacitance										
Symbol	Parameter	Conditions	$T_A = +25^\circ\text{C}$		Units					
			V_{CC}	Typical						
C_{IN}	Input Capacitance	$V_I = 0V \text{ or } V_{CC}$	3.3	6	pF					
C_{OUT}	Output Capacitance	$V_I = 0V \text{ or } V_{CC}$	3.3	7	pF					
C_{PD}	Power Dissipation Capacitance	Outputs Enabled	$f = 10\text{ MHz}, C_L = 50\text{ pF}$	3.3	20	pF				
				2.5	20					

AC Loading and Waveforms

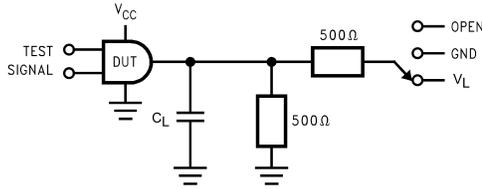


FIGURE 1. AC Test Circuit

TABLE 1. Values for Figure 1

TEST	SWITCH
t_{PLH} , t_{PHL}	Open
t_{PZL} , t_{PLZ}	V_L
t_{PZH} , t_{PHZ}	GND

TABLE 2. Variable Matrix
(Input Characteristics: $f = 1\text{MHz}$; $t_r = t_f = 2\text{ns}$; $Z_0 = 50\Omega$)

Symbol	V_{CC}			
	$3.3\text{V} \pm 0.3\text{V}$	2.7V	$2.5\text{V} \pm 0.2\text{V}$	$1.8\text{V} \pm 0.15\text{V}$
V_{mi}	1.5V	1.5V	$V_{CC}/2$	$V_{CC}/2$
V_{mo}	1.5V	1.5V	$V_{CC}/2$	$V_{CC}/2$
V_X	$V_{OL} + 0.3\text{V}$	$V_{OL} + 0.3\text{V}$	$V_{OL} + 0.15\text{V}$	$V_{OL} + 0.15\text{V}$
V_Y	$V_{OH} - 0.3\text{V}$	$V_{OH} - 0.3\text{V}$	$V_{OH} - 0.15\text{V}$	$V_{OH} - 0.15\text{V}$
V_L	6V	6V	$V_{CC} * 2$	$V_{CC} * 2$

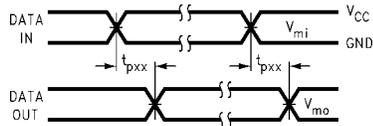


FIGURE 2. Waveform for Inverting and Non-Inverting Functions

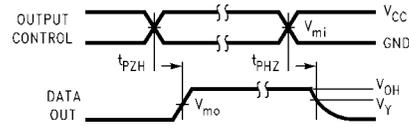


FIGURE 3. 3-STATE Output HIGH Enable and Disable Times for Low Voltage Logic

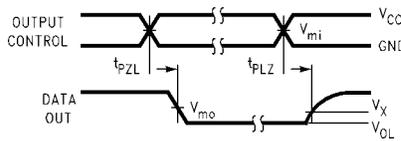


FIGURE 4. 3-STATE Output LOW Enable and Disable Times for Low Voltage Logic

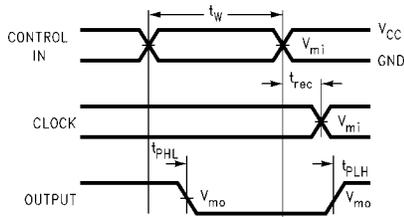


FIGURE 5. Propagation Delay, Pulse Width and t_{rec} Waveforms

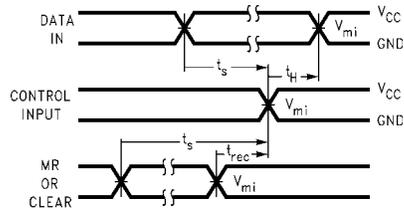
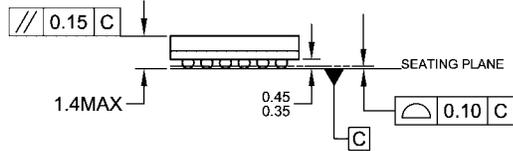
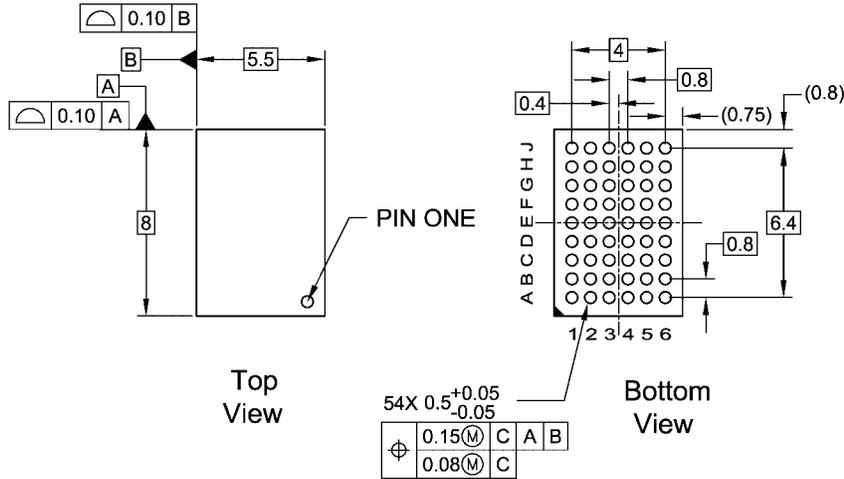


FIGURE 6. Setup Time, Hold Time and Recovery Time for Low Voltage Logic

Physical Dimensions inches (millimeters) unless otherwise noted



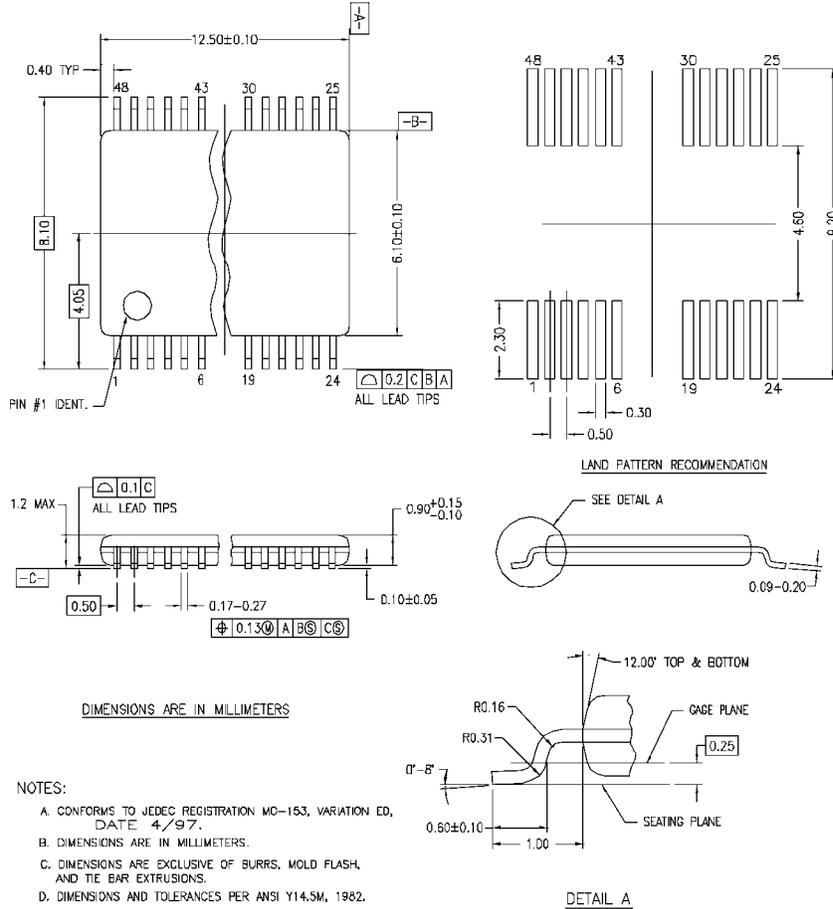
NOTES:

- A. THIS PACKAGE CONFORMS TO JEDEC MO-205
- B. ALL DIMENSIONS IN MILLIMETERS
- C. LAND PATTERN RECOMMENDATION: NSMD (Non Solder Mask Defined)
.35MM DIA PADS WITH A SOLDERMASK OPENING OF .45MM CONCENTRIC TO PADS
- D. DRAWING CONFORMS TO ASME Y14.5M-1994

BGA54ArevD

**54-Ball Fine-Pitch Ball Grid Array (FBGA), JEDEC MO-205, 5.5mm Wide
Package Number BGA54A
(Preliminary)**

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



MTD48REV C

48-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide Package Number MTD48

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